JM Test Systems located in Baton Rouge, Louisiana, graciously hosted the NCSLI Gulf Coast Section Meeting on April 28th, 2015 at their new electrical safety testing laboratory. After a brief meet-and-greet, the meeting was kicked off at 9:00 by the Section Coordinator Brian King of A2Research. He, and the President of JM Test Systems Mr. Scott Morrison, welcomed the 26 attendees and briefly went over the day’s agenda before introducing Dr. Hy Tran.

Dr. Tran, Sandia National Laboratories and the NCSLI Central Division VP, gave the NCSLI Board of Director’s update and encouraged everyone to attend the upcoming NCSLI Conference to be held in Grapevine, Texas.

Mike Scott, of The Modal Shop was next on the agenda. Mike gave a 45 minute presentation on the “Calibration and Verification of Vibration Protection Systems.” His presentation touched on the advantages and challenges that exist in the calibration process.

After a short break, the attendees enjoyed a tour of JM Test Systems new Electrical Safety Laboratory and the Metrology facilities. Many compliments of the size and scope of the facilities were shared by many of the participants.

Next, we broke for a wonderful lunch which was graciously provided by JM Test Systems. The Jambalaya was highly talked about and enjoyed by all!

Next up was Jason Dewar of Fluke Calibration who gave an informative presentation on the “HART Communication Protocol.” He provided a brief history of the origins of the protocol as well as outlining the advantages associated with the technology.

Our final presentation was given by Richard Roddis of Fluke Calibration, whose topic was of special interest to those in attendance. His presentation was entitled “Fluke’s Artifact Calibration and Its Use in Calibration of 8.5 Digit DMM’s.” Richard was able to give the attendees the necessary tools in which to analyze their own use scenarios and perhaps take advantage of 24 hour specifications or 90 day specifications of laboratory standards that they may already have.

The day was concluded with a group photo and a thanking of all in attendance for their participation, the speakers for their contributions, and JM Test Systems for hosting this very successful meeting.

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